

# Feature Defect Prediction

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## ABSTRACT

**ACM Reference Format:**

. 2020. Feature Defect Prediction. In *Proceedings of ACM Conference (Conference'17)*. ACM, New York, NY, USA, ?? pages.

## 1 INTRODUCTION

## 2 BACKGROUND

## 3 METHODOLOGY

### 3.1 Subject Systems

### 3.2 Conceptual Structures and Metrics

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*Conference'17, July 2017, Washington, DC, USA*

2020. ACM ISBN 978-x-xxxx-xxxx-x/YY/MM...\$15.00